




Issue Classification 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/711,046	LEE, JEN-FENG	
	Examiner	Art Unit	
	Mark Spisich	1744	

ISSUE CLASSIFICATION										
ORIGINAL				CROSS REFERENCE(S)						
CLASS		SUBCLASS		CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)					
15		28		15	22.1	22.2				
INTERNATIONAL CLASSIFICATION										
A	4	6	B	5/04						
A	6	1	C	17/22						
				/						
				/						
				/						
-- (Assistant Examiner) (Date)				 Mark Spisich Primary Examiner Art Unit 1744 (Primary Examiner)			Total Claims Allowed: 5			
 (Legal Instruments Examiner) (Date)							O.G. Print Claim(s)		O.G. Print Fig.	
							1		1	

<input checked="" type="checkbox"/> Claims renumbered in the same order as presented by applicant										<input type="checkbox"/> CPA		<input type="checkbox"/> T.D.		<input type="checkbox"/> R.1.47	
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